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Applications of "Embedded - Microcontrollers"

Details	
Product Status	Not For New Designs
Core Processor	STM8A
Core Size	8-Bit
Speed	24MHz
Connectivity	CANbus, I²C, LINbus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	68
Program Memory Size	128KB (128K x 8)
Program Memory Type	FLASH
EEPROM Size	2K x 8
RAM Size	6K x 8
Voltage - Supply (Vcc/Vdd)	3V ~ 5.5V
Data Converters	A/D 16x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	80-LQFP
Supplier Device Package	80-LQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm8af52aatax

5.7 Timers

5.7.1 Watchdog timers

The watchdog system is based on two independent timers providing maximum security to the applications. The watchdog timer activity is controlled by the application program or option bytes. Once the watchdog is activated, it cannot be disabled by the user program without going through reset.

Window watchdog timer

The window watchdog is used to detect the occurrence of a software fault, usually generated by external interferences or by unexpected logical conditions, which cause the application program to abandon its normal sequence.

The window function can be used to trim the watchdog behavior to match the application timing perfectly. The application software must refresh the counter before time-out and during a limited time window. If the counter is refreshed outside this time window, a reset is issued.

Independent watchdog timer

The independent watchdog peripheral can be used to resolve malfunctions due to hardware or software failures.

It is clocked by the 128 kHz LSI internal RC clock source, and thus stays active even in case of a CPU clock failure. If the hardware watchdog feature is enabled through the device option bits, the watchdog is automatically enabled at power-on, and generates a reset unless the key register is written by software before the counter reaches the end of count.

5.7.2 Auto-wakeup counter

This counter is used to cyclically wakeup the device in Active-halt mode. It can be clocked by the internal 128 kHz internal low-frequency RC oscillator or external clock.

LSI clock can be internally connected to TIM3 input capture channel 1 for calibration.

5.7.3 Beeper

This function generates a rectangular signal in the range of 1, 2 or 4 kHz which can be output on a pin. This is useful when audible sounds without interference need to be generated for use in the application.

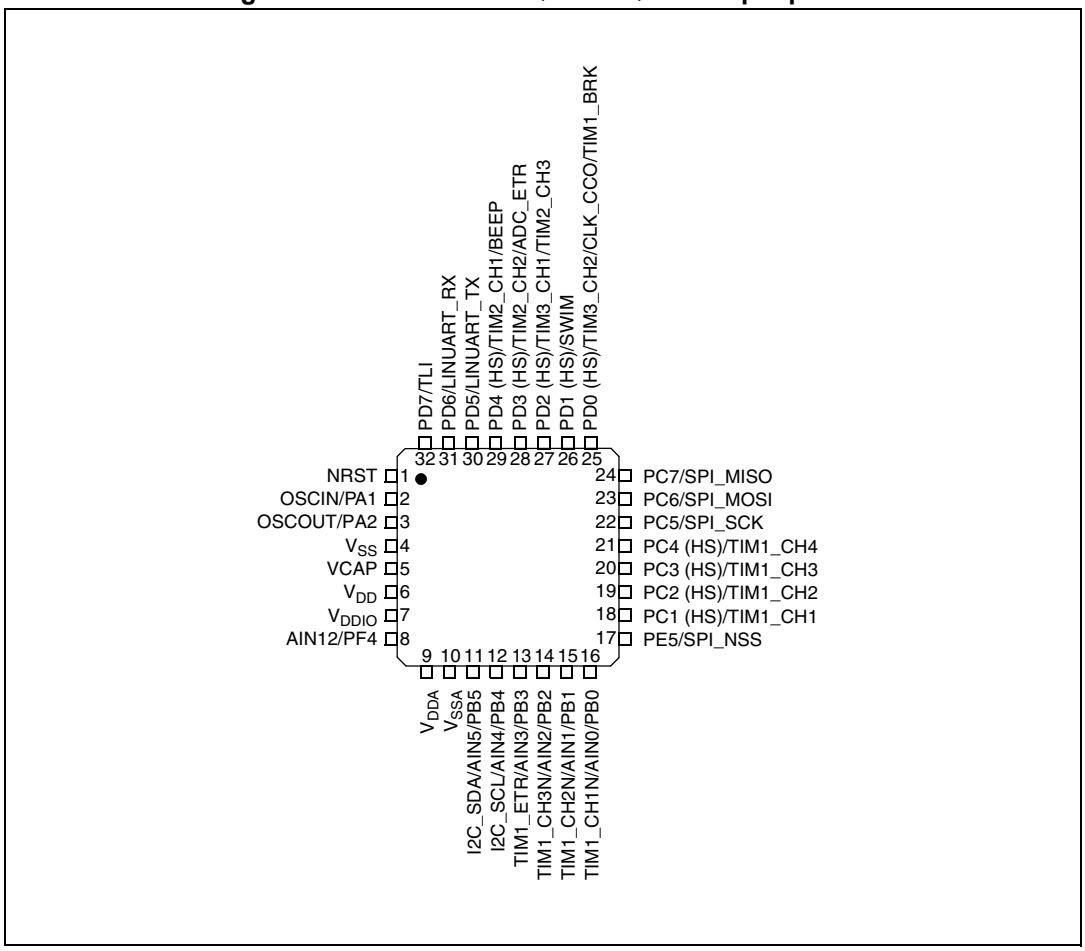
5.7.4 Advanced control and general purpose timers

STM8A devices described in this datasheet, contain up to three 16-bit advanced control and general purpose timers providing nine CAPCOM channels in total. A CAPCOM channel can be used either as input compare, output compare or PWM channel. These timers are named TIM1, TIM2 and TIM3.

Detailed feature list:

- Full duplex, asynchronous communications
- NRZ standard format (mark/space)
- High-precision baud rate generator system
  - Common programmable transmit and receive baud rates up to $f_{MASTER}/16$
- Programmable data word length (8 or 9 bits)
- Configurable stop bits: Support for 1 or 2 stop bits
- LIN master mode:
  - LIN break and delimiter generation
  - LIN break and delimiter detection with separate flag and interrupt source for readback checking.
- Transmitter clock output for synchronous communication
- Separate enable bits for transmitter and receiver
- Transfer detection flags:
  - Receive buffer full
  - Transmit buffer empty
  - End of transmission flags
- Parity control:
  - Transmits parity bit
  - Checks parity of received data byte
- Four error detection flags:
  - Overrun error
  - Noise error
  - Frame error
  - Parity error
- Six interrupt sources with flags:
  - Transmit data register empty
  - Transmission complete
  - Receive data register full
  - Idle line received
  - Parity error
  - LIN break and delimiter detection
- Two interrupt vectors:
  - Transmitter interrupt
  - Receiver interrupt
- Reduced power consumption mode
- Wakeup from mute mode (by idle line detection or address mark detection)
- Two receiver wakeup modes:
  - Address bit (MSB)
  - Idle line

Figure 6. STM8AF62xx LQFP/VFQFPN 32-pin pinout



1. HS stands for high sink capability.

Table 12. Memory model 128K

Flash program memory size	Flash program memory end address	RAM size	RAM end address	Stack roll-over address
128 K	0x00 27FFF	6 K	0x00 17FF	0x00 1400
64 K	0x00 17FFF			
32 K	0x00 0FFFF			

7.2 Register map

In this section the memory and register map of the devices covered by this datasheet is described. For a detailed description of the functionality of the registers, refer to STM8S series and STM8AF series 8-bit microcontrollers reference manual, RM0016.

Table 13. I/O port hardware register map

Address	Block	Register label	Register name	Reset status
0x00 5000	Port A	PA_ODR	Port A data output latch register	0x00
0x00 5001		PA_IDR	Port A input pin value register	0xXX(1)
0x00 5002		PA_DDR	Port A data direction register	0x00
0x00 5003		PA_CR1	Port A control register 1	0x00
0x00 5004		PA_CR2	Port A control register 2	0x00
0x00 5005	Port B	PB_ODR	Port B data output latch register	0x00
0x00 5006		PB_IDR	Port B input pin value register	0xXX(1)
0x00 5007		PB_DDR	Port B data direction register	0x00
0x00 5008		PB_CR1	Port B control register 1	0x00
0x00 5009		PB_CR2	Port B control register 2	0x00
0x00 500A	Port C	PC_ODR	Port C data output latch register	0x00
0x00 500B		PB_IDR	Port C input pin value register	0xXX(1)
0x00 500C		PC_DDR	Port C data direction register	0x00
0x00 500D		PC_CR1	Port C control register 1	0x00
0x00 500E		PC_CR2	Port C control register 2	0x00
0x00 500F	Port D	PD_ODR	Port D data output latch register	0x00
0x00 5010		PD_IDR	Port D input pin value register	0xXX(1)
0x00 5011		PD_DDR	Port D data direction register	0x00
0x00 5012		PD_CR1	Port D control register 1	0x02
0x00 5013		PD_CR2	Port D control register 2	0x00

Low-speed internal RC oscillator (LSI)

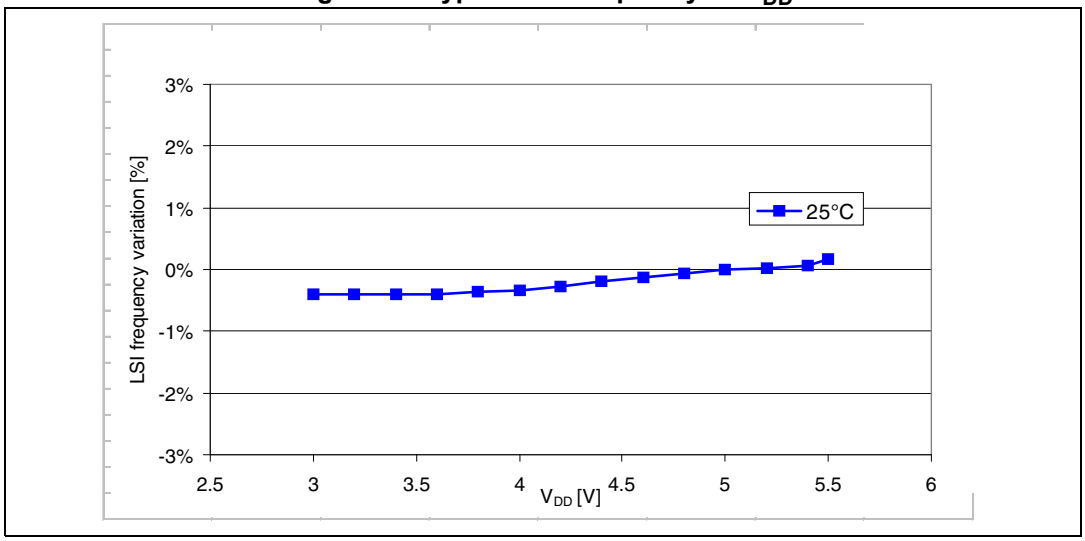
Subject to general operating conditions for V_{DD} and T_A.

Table 34. LSI oscillator characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f_{LSI}	Frequency	-	112	128	144	kHz
$t_{su(LSI)}$	LSI oscillator wakeup time	-	-	-	7(1)	µs

1. Guaranteed by characterization results, not tested in production.

Figure 22. Typical LSI frequency vs V_{DD}



2. Guaranteed by design.
3. Guaranteed by characterization results, not tested in production.

Figure 23. Typical V_{IL} and V_{IH} vs V_{DD} @ four temperatures

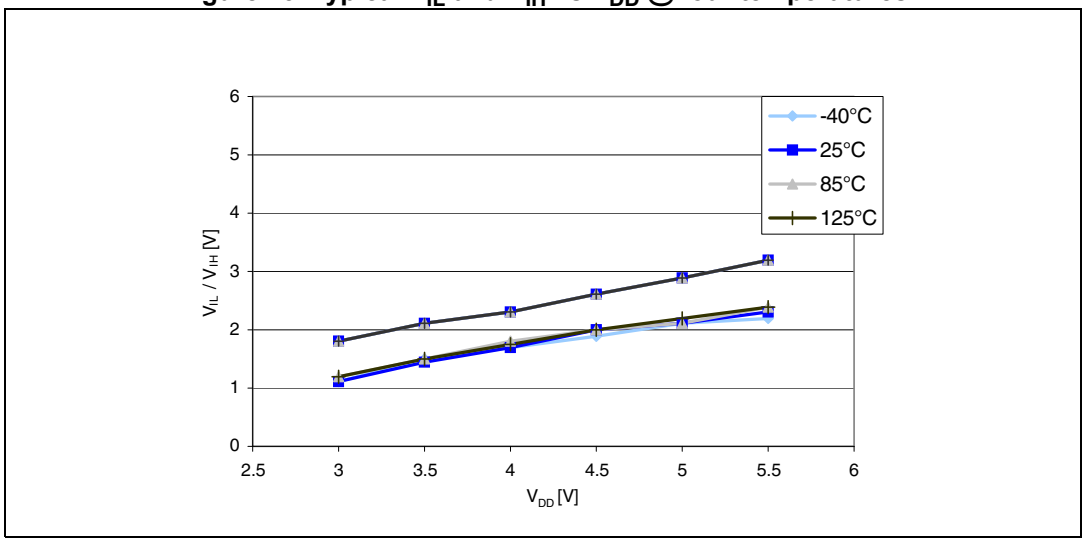


Figure 24. Typical pull-up resistance R_{PU} vs V_{DD} @ four temperatures

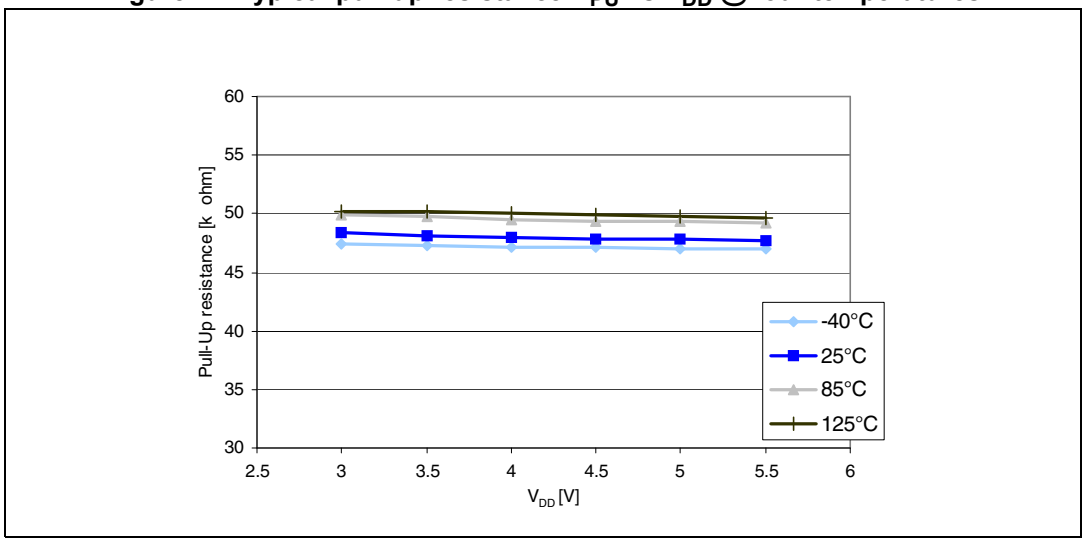
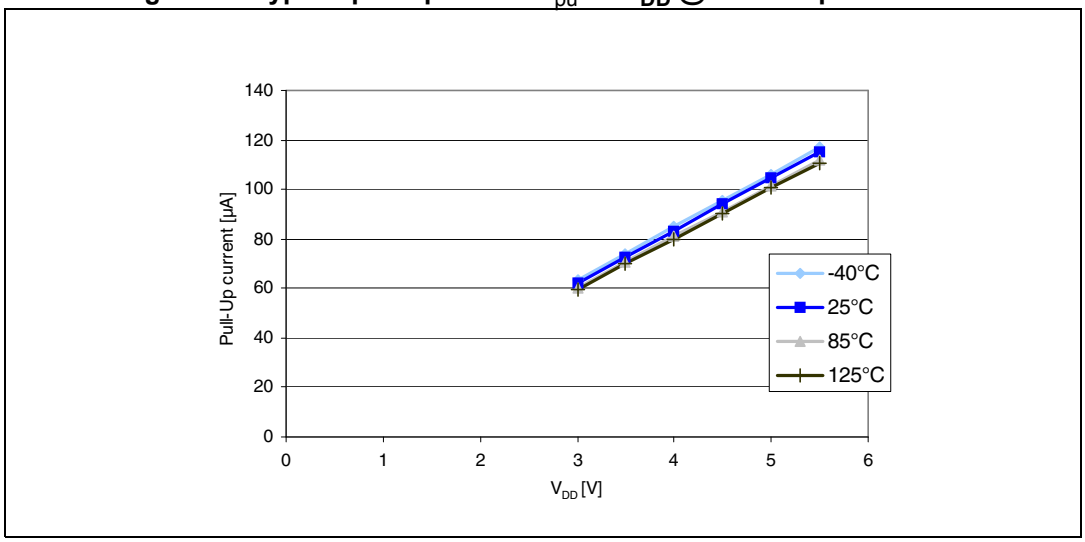


Figure 25. Typical pull-up current I_{pu} vs V_{DD} @ four temperatures(1)



1. The pull-up is a pure resistor (slope goes through 0).

Typical output level curves

Figure 26 to *Figure 35* show typical output level curves measured with output on a single pin.

Figure 26. Typ. V_{OL} @ V_{DD} = 3.3 V (standard ports)

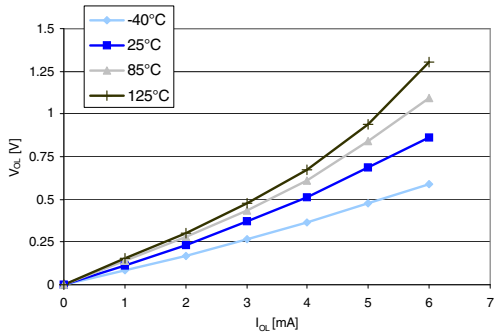


Figure 27. Typ. V_{OL} @ V_{DD} = 5.0 V (standard ports)

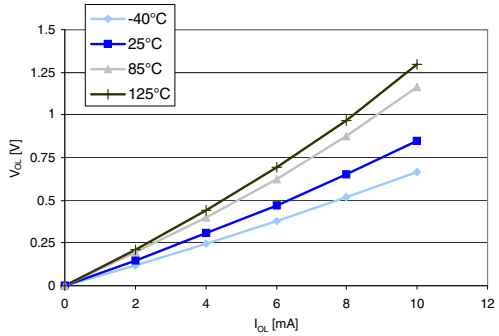


Figure 28. Typ. V_{OL} @ V_{DD} = 3.3 V (true open drain ports)

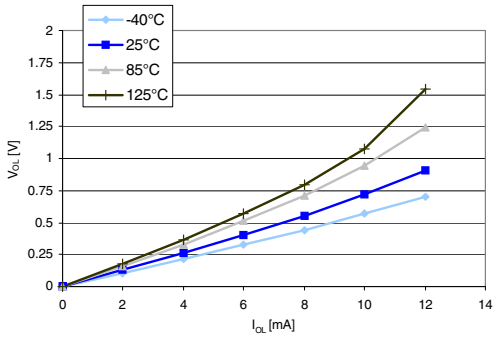


Figure 29. Typ. V_{OL} @ V_{DD} = 5.0 V (true open drain ports)

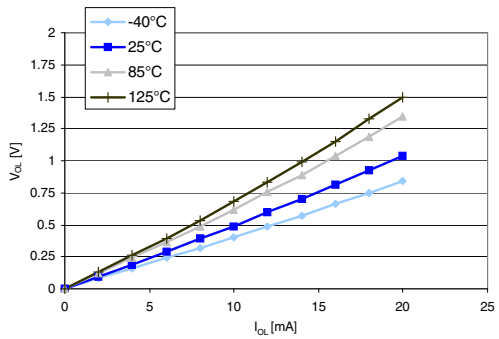


Figure 37. Typical NRST pull-up resistance R_{PU} vs V_{DD}

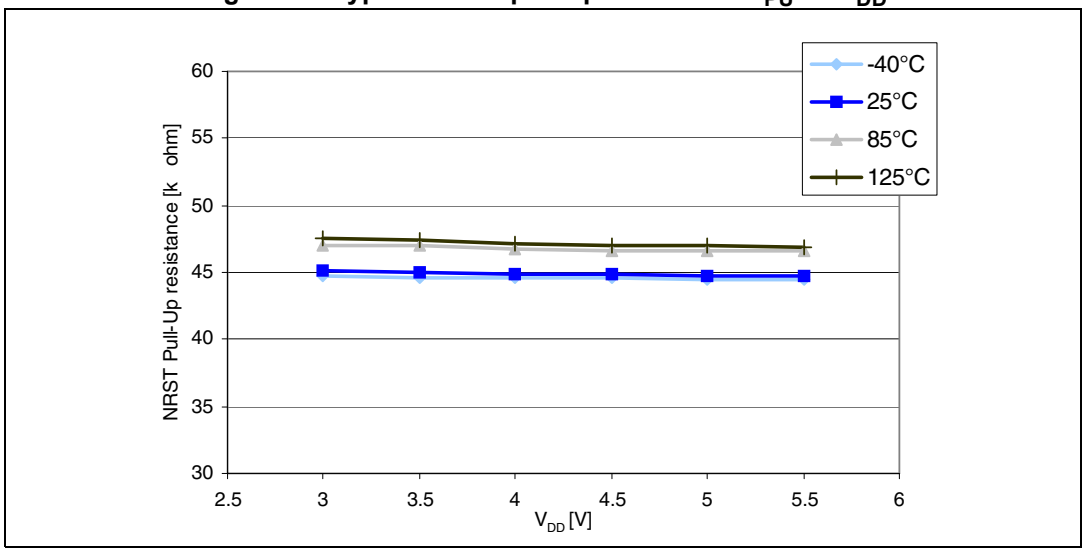
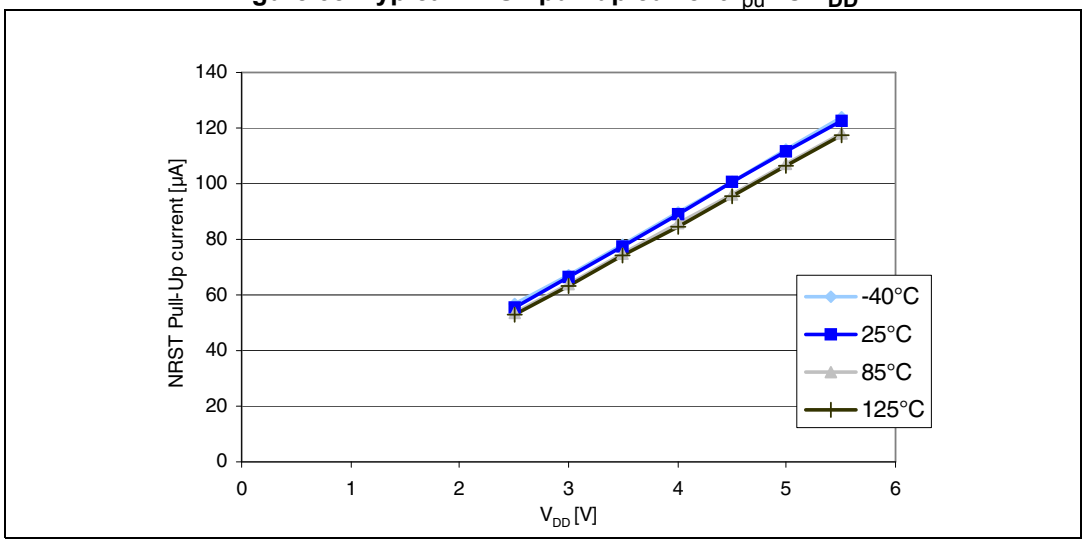


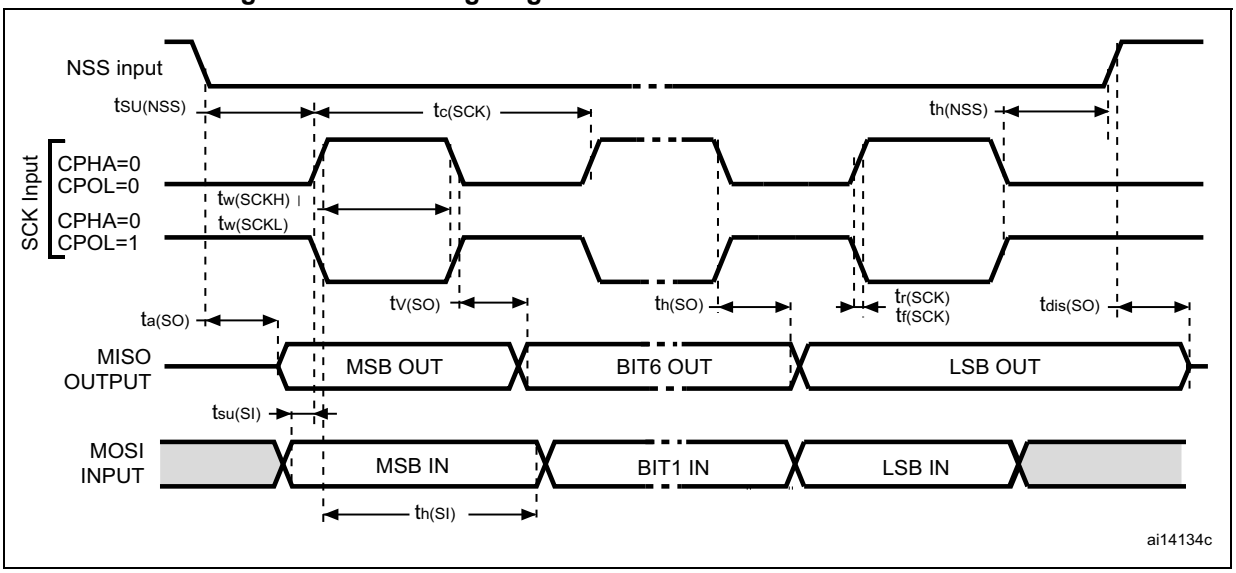
Figure 38. Typical NRST pull-up current I_{pu} vs V_{DD}



The reset network shown in *Figure 39* protects the device against parasitic resets. The user must ensure that the level on the NRST pin can go below $V_{IL(NRST)}$ max (see *Table 39: NRST pin characteristics*), otherwise the reset is not taken into account internally.

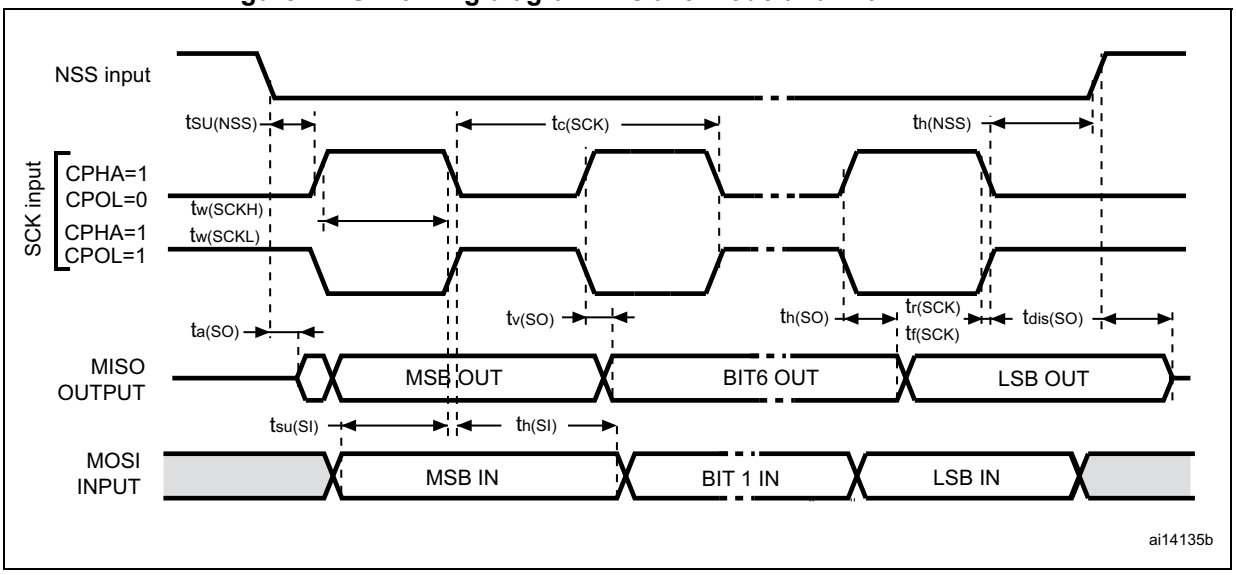
For power consumption sensitive applications, the external reset capacitor value can be reduced to limit the charge/discharge current. If NRST signal is used to reset external circuitry, attention must be taken to the charge/discharge time of the external capacitor to fulfill the external devices reset timing conditions. Minimum recommended capacity is 10 nF.

Figure 40. SPI timing diagram in slave mode and with CPHA = 0



1. Measurement points are at CMOS levels: 0.3 V_{DD} and 0.7 V_{DD}.

Figure 41. SPI timing diagram in slave mode and with CPHA = 1



1. Measurement points are at CMOS levels: 0.3 V_{DD} and 0.7 V_{DD}.

10.3.11 10-bit ADC characteristics

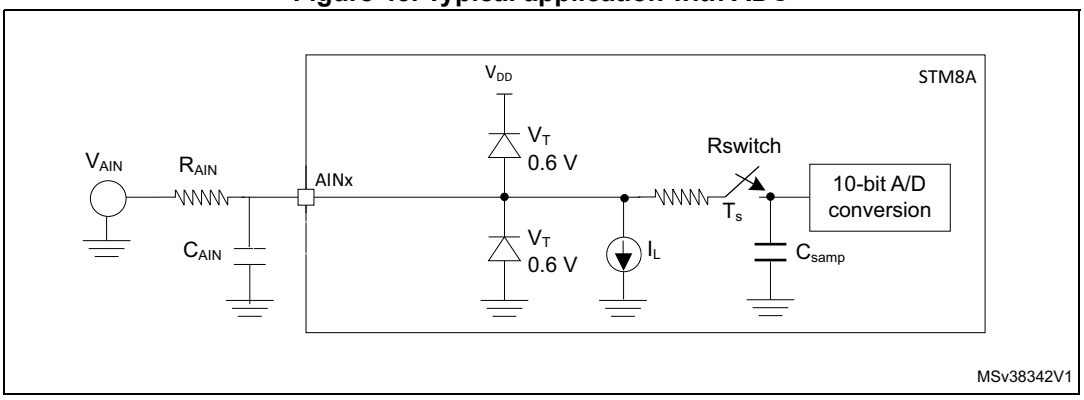
Subject to general operating conditions for V_{DDA}, f_{MASTER} and T_A unless otherwise specified.

Table 43. ADC characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f_{ADC}	ADC clock frequency	-	111 kHz	-	4 MHz	kHz/MHz
V_{DDA}	Analog supply	-	3	-	5.5	V
V_{REF+}	Positive reference voltage	-	2.75	-	V_{DDA}	
V_{REF-}	Negative reference voltage	-	V_{SSA}	-	0.5	
V_{AIN}	Conversion voltage range(1)	-	V_{SSA}	-	V_{DDA}	
		Devices with external V_{REF+}/ V_{REF-} pins	V_{REF-}	-	V_{REF+}	
C_{samp}	Internal sample and hold capacitor	-	-	-	3	pF
t_S(1)	Sampling time (3 x 1/f_{ADC})	f_{ADC} = 2 MHz	-	1.5	-	µs
		f_{ADC} = 4 MHz	-	0.75	-	
t_{STAB}	Wakeup time from standby	f_{ADC} = 2 MHz	-	7	-	
		f_{ADC} = 4 MHz	-	3.5	-	
t_{CONV}	Total conversion time including sampling time (14 x 1/f_{ADC})	f_{ADC} = 2 MHz	-	7	-	
		f_{ADC} = 4 MHz	-	3.5	-	
R_{switch}	Equivalent switch resistance	-	-	-	30	kΩ

1. During the sample time, the sampling capacitance, C_{samp} (3 pF typ), can be charged/discharged by the external source. The internal resistance of the analog source must allow the capacitance to reach its final voltage level within t_S. After the end of the sample time t_S, changes of the analog input voltage have no effect on the conversion result.

Figure 43. Typical application with ADC



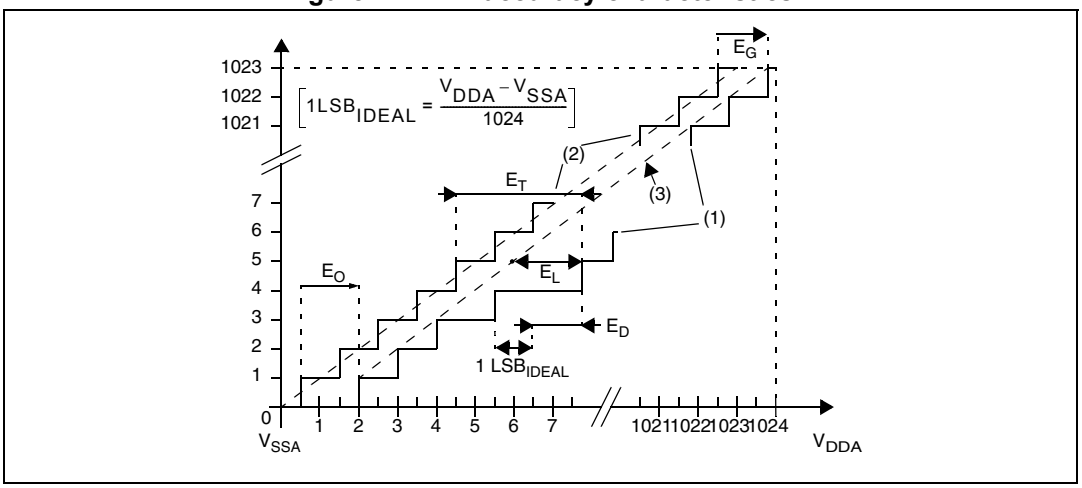
1. Legend: R_{AIN} = external resistance, C_{AIN} = capacitors, C_{samp} = internal sample and hold capacitor.

Table 44. ADC accuracy for V_{DDA} = 5 V

Symbol	Parameter	Conditions	Typ	Max(1)	Unit
$\|E_T\|$	Total unadjusted error(2)	f_{ADC} = 2 MHz	1.4	3(3)	LSB
$\|E_O\|$	Offset error(2)		0.8	3	
$\|E_G\|$	Gain error(2)		0.1	2	
$\|E_D\|$	Differential linearity error(2)		0.9	1	
$\|E_L\|$	Integral linearity error(2)		0.7	1.5	
$\|E_T\|$	Total unadjusted error(2)	f_{ADC} = 4 MHz	1.9(4)	4(4)	
$\|E_O\|$	Offset error(2)		1.3(4)	4(4)	
$\|E_G\|$	Gain error(2)		0.6(4)	3(4)	
$\|E_D\|$	Differential linearity error(2)		1.5(4)	2(4)	
$\|E_L\|$	Integral linearity error(2)		1.2(4)	1.5(4)	

1. Guaranteed by characterization results, not tested in production.
2. ADC accuracy vs. injection current: Any positive or negative injection current within the limits specified for $I_{INJ(PIN)}$ and $\Sigma I_{INJ(PIN)}$ in *Section 10.3.6* does not affect the ADC accuracy.
3. TUE 2LSB can be reached on specific sales types on the whole temperature range.
4. Target values.

Figure 44. ADC accuracy characteristics



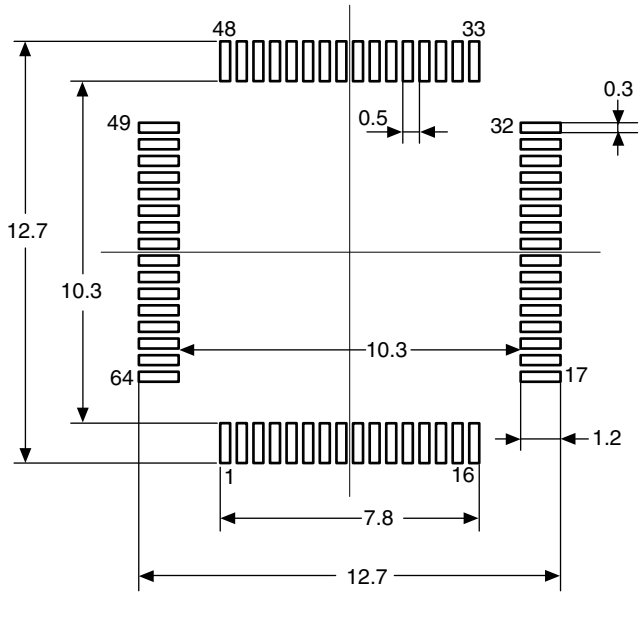
1. Example of an actual transfer curve
2. The ideal transfer curve
3. End point correlation line
   E_T = Total unadjusted error: Maximum deviation between the actual and the ideal transfer curves.
   E_O = Offset error: Deviation between the first actual transition and the first ideal one.
   E_G = Gain error: Deviation between the last ideal transition and the last actual one.
   E_D = Differential linearity error: Maximum deviation between actual steps and the ideal one.
   E_L = Integral linearity error: Maximum deviation between any actual transition and the end point correlation line.

Table 50. LQFP64 - 64-pin, 10 x 10 mm low-profile quad flat package mechanical data (continued)

Symbol	millimeters			inches[1]		
	Min	Typ	Max	Min	Typ	Max
E3	-	7.500	-	-	0.2953	-
e	-	0.500	-	-	0.0197	-
K	0°	3.5°	7°	0°	3.5°	7°
L	0.450	0.600	0.750	0.0177	0.0236	0.0295
L1	-	1.000	-	-	0.0394	-
ccc	-	-	0.080	-	-	0.0031

1. Values in inches are converted from mm and rounded to 4 decimal digits.

Figure 49. LQFP64 - 64-pin, 10 x 10 mm low-profile quad flat package recommended footprint



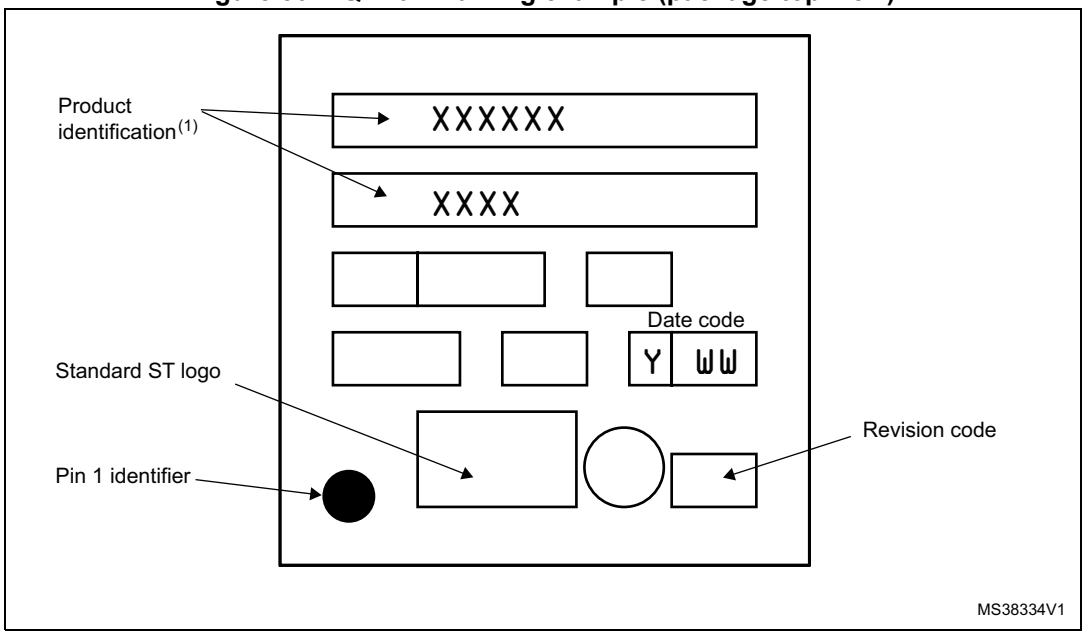
1. Dimensions are expressed in millimeters.

Device marking

The following figure gives an example of topside marking orientation versus pin 1 identifier location.

Other optional marking or inset/upset marks, which identify the parts throughout supply chain operations, are not indicated below.

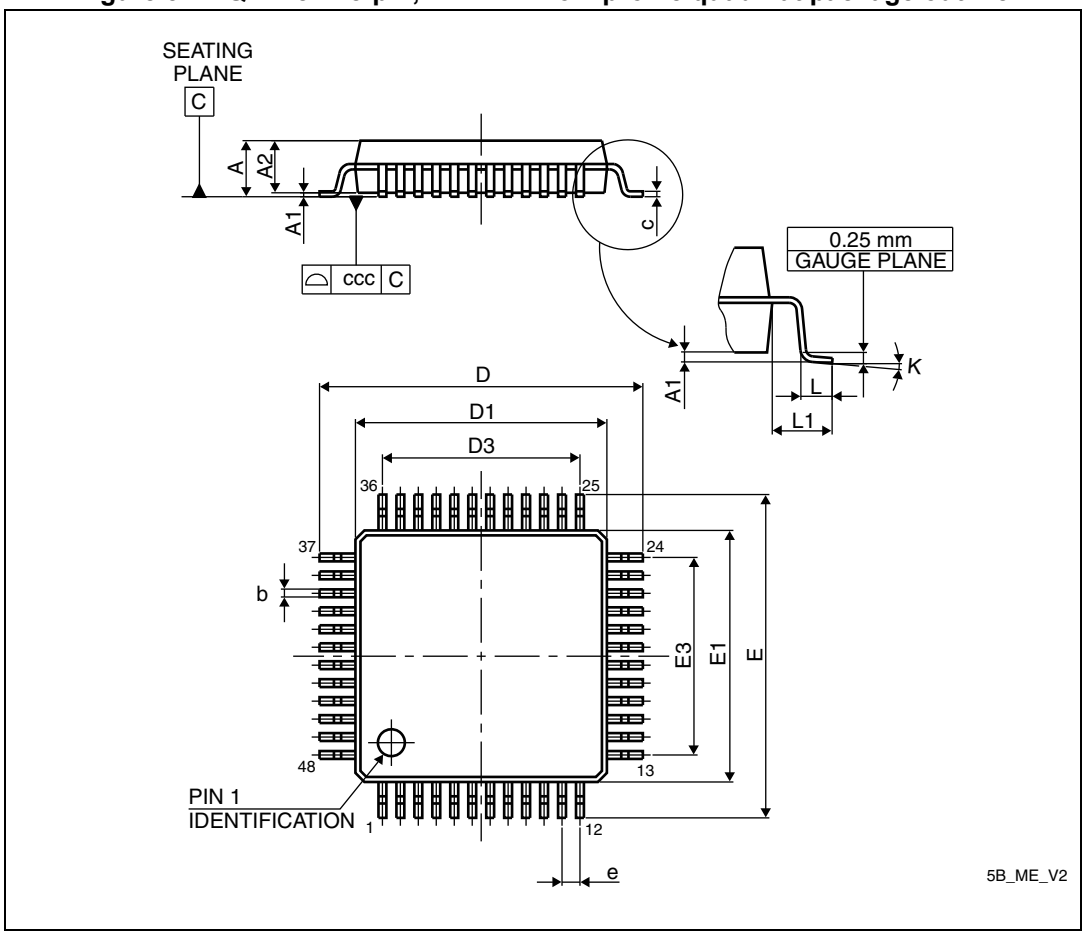
Figure 50. LQFP64 marking example (package top view)



1. Parts marked as "ES","E" or accompanied by an Engineering Sample notification letter are not yet qualified and therefore not approved for use in production. ST is not responsible for any consequences resulting from such use. In no event will ST be liable for the customer using any of these engineering samples in production. ST's quality department must be contacted to run a qualification activity prior to any decision to use these engineering samples.

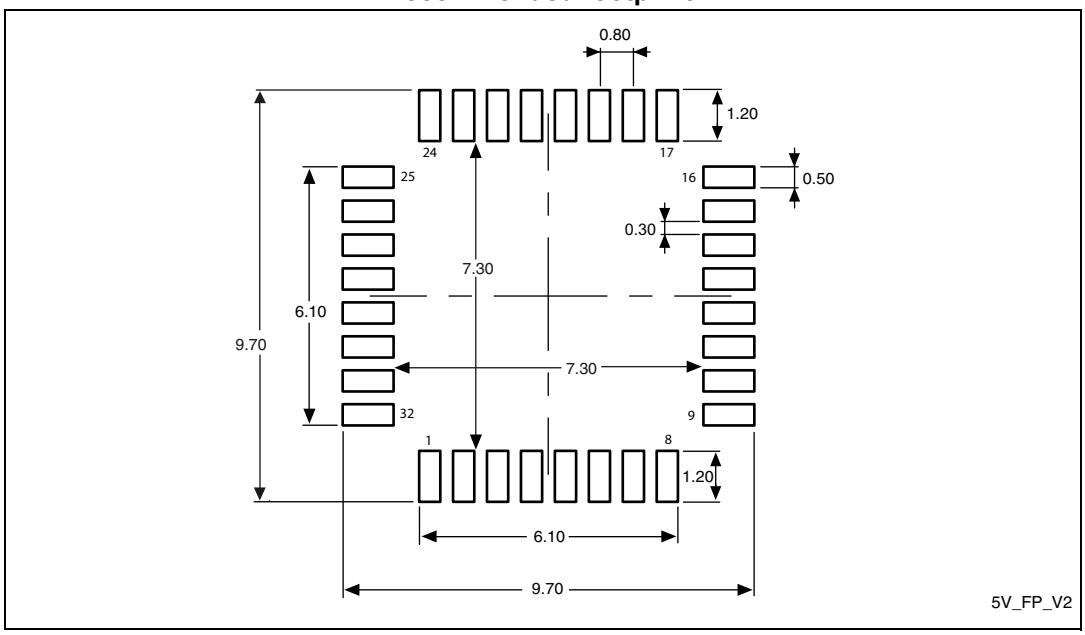
11.3 LQFP48 package information

Figure 51. LQFP48 - 48-pin, 7 x 7 mm low-profile quad flat package outline



1. Drawing is not to scale.

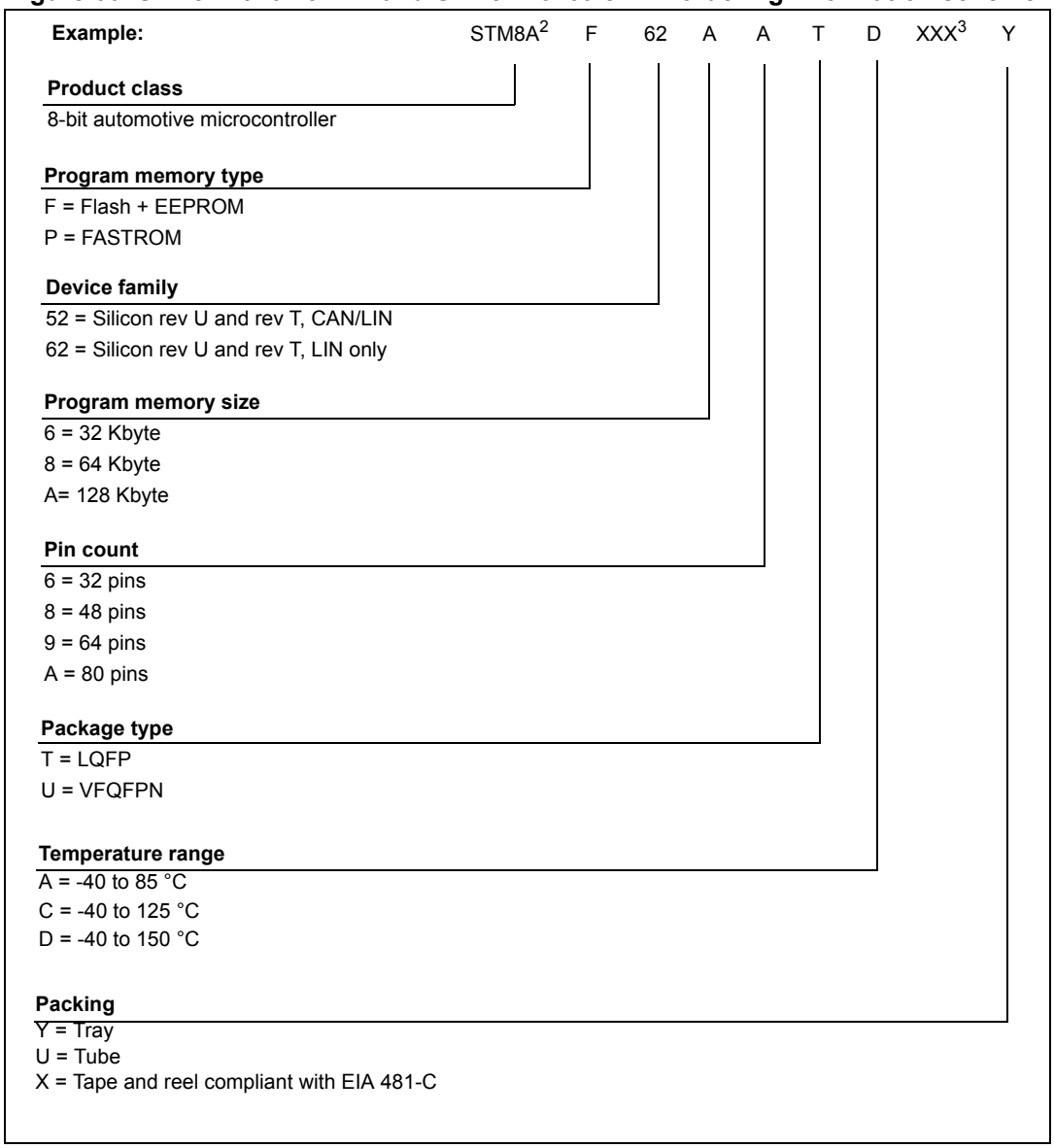
Figure 55. LQFP32 - 32-pin, 7 x 7 mm low-profile quad flat package recommended footprint



1. Dimensions are expressed in millimeters.

12 Ordering information

Figure 60. STM8AF526x/8x/Ax and STM8AF6269/8x/Ax ordering information scheme[1]



1. For a list of available options (e.g. memory size, package) and orderable part numbers or for further information on any aspect of this device, please go to *www.st.com* or contact the nearest ST Sales Office.
2. Qualified and characterized according to AEC Q100 and Q003 or equivalent, advanced screening according to AEC Q001 and Q002 or equivalent.
3. Customer specific FASTROM code or custom device configuration. This field shows 'SSS' if the device contains a super set silicon, usually equipped with bigger memory and more I/Os. This silicon is supposed to be replaced later by the target silicon.

13.3 Programming tools

During the development cycle, STice provides in-circuit programming of the STM8A Flash microcontroller on the application board via the SWIM protocol. Additional tools are to include a low-cost in-circuit programmer as well as ST socket boards, which provide dedicated programming platforms with sockets for programming the STM8A.

For production environments, programmers will include a complete range of gang and automated programming solutions from third-party tool developers already supplying programmers for the STM8 family.

Table 55. Document revision history (continued)

Date	Revision	Changes
01-Jul-2009	4 (continued)	Removed table*: Total current consumption and timing in halt, fast active halt and slow active halt modes at V_{DD} = 3.3 V.* Added *Table 28: Oscillator current consumption.* Added *Table 29: Programming current consumption.* Updated *Table 30: Typical peripheral current consumption VDD = 5.0 V* Updated *Table 31: HSE external clock characteristics.* Updated *Table 32: HSE oscillator characteristics.* *Table 20: HSE oscillator circuit diagram:* changed 'consumption control' to 'current control' *Section : HSE oscillator critical gm formula:* clarified formula Updated *Table 33: HSI oscillator characteristics.* Removed *'RAM and hardware registers'* Removed *Table: RAM and hardware registers.* Updated *Table 35: Flash program memory/data EEPROM memory* Added *Table 36: Flash program memory.* Added *Table 37: Data memory.* Updated *Table 38: I/O static characteristics.* Updated *Table 39: NRST pin characteristics.* Updated *Table 40: TIM 1, 2, 3, and 4 electrical specifications* *Section 10.3.9: SPI interface:* changed title from "SPI serial peripheral interface". Updated *Table 41: SPI characteristics.* *Figure 40: SPI timing diagram in slave mode and with CPHA = 0*: Changed title and added footnote. *Figure 41: SPI timing diagram in slave mode and with CPHA = 1:* changed the title. Updated *Table 43: ADC characteristics.* Updated *Figure 43: Typical application with ADC.* Removed *Table: ADC accuracy for VDDA = 3.3 V.* Updated *Table 44: ADC accuracy for VDDA = 5 V.* Updated *Table 46: EMI data.* Updated *Table 48: Electrical sensitivities.* Added text about Ecopack in the *Section 11: Package information.* *Figure 48: LQFP64 - 64-pin, 10 x 10 mm low-profile quad flat package outline:* deleted footnote. Updated *Figure 60: STM8AF526x/8x/Ax and STM8AF6269/8x/Ax ordering information scheme1*. Added *Section 13: STM8 development tools.*
22-Oct-2009	5	Updated *Table 1: Device summary*: added STM8AF5178, STM8AF519A and STM8AF619A.

Table 55. Document revision history (continued)

Date	Revision	Changes
13-Apr-2010	6	Updated title on cover page. Modified cover page header to clarify the part numbers covered by the datasheets. Updated footnote on *Table 1: Device summary* to add 'P' order codes. Changed definition of 'P' order codes. 'Q' order codes (FASTROM and EEPROM) removed. Reorganized the content of *Section 5: Product overview*. *Table 11: STM8AF526x/8x/Ax and STM8AF6269/8x/Ax pin description* updated PD7/TLI alternate function, removed caution note for PD6/ LINUART_RX, and added note to PA1/OSCIN. Renamed *Section 7: Memory and register map*, and merged content with *Section: Register map*. Updated *Figure 8: Register and memory map*. Renamed BL_EN and NBL_EN, BL and NBL, respectively, in *Table 18: Option bytes*. Updated AFR4 definition in *Table 19: Option byte description*. Added C_{EXT} in *Table 24: General operating conditions*, and *Section 10.3.1: VCAP external capacitor*. Updated t_{VDD} in *Table 25: Operating conditions at power-up/power-down*. Moved *Table 30: Typical peripheral current consumption VDD = 5.0 V* to *Section : Current consumption for on-chip peripherals*. Removed $V_{ESD(MM)}$ from *Table 47: ESD absolute maximum ratings*. Updated *Section 12: Ordering information* to the devices supported by the datasheet. Updated *Section 13: STM8 development tools*.
08-Jul-2010	7	Added STM8AF5168 and STM8AF518A part number in *Figure 4*, and STM8AF618A in *Figure 5*. Added STM8AF52xx, STM8AF6269, STM8AF628x, and STM8AF62Ax. Updated D temperature range to -40 to 150°C. Updated number of I/Os on cover page. Added *Table 23: Operating lifetime*. Restored $V_{ESD(MM)}$ from *Table 47: ESD absolute maximum ratings*. *Table 24: General operating conditions*: updated V_{CAP} information. ESL parameter, and range D maximum junction temperature (T_J). Added STM8AF52xx and STM8AF62xx, and footnote in *Section 12: Ordering information*. Updated *Section 13: STM8 development tools*: added *Table: Product evolution summary*, and split the beCAN time triggered communication mode limitation in two sections.

Table 55. Document revision history (continued)

Date	Revision	Changes
31-Mar-2014	10 (continued)	Added: – *Figure 7: STM8AF52x6 VFQFPN32 32-pin pinout;* – the caution in *Section 5.10: Input/output specifications,* – The table footnote “Not recommended for new designs” to *Table: STM8AF/H/P51xx product line-up with CAN* and *Table: STM8AF/H/P61xx product line-up without CAN.* – The figure footnotes to *Figure 7: STM8AF52x6 VFQFPN32 32-pin pinout* and *Figure: VFQFPN 32-lead very thin fine pitch quad flat no-lead package (5 x 5)*
13-Jun-2014	11	Added STM8AF52A6 part number.
09-Jun-2015	12	Added: – the third table footnote to *Table 25: Operating conditions at power-up/power-down*, – *Figure 47: LQFP80 marking example (package top view)*, – *Figure 50: LQFP64 marking example (package top view)*, – *Figure 53: LQFP48 marking example (package top view)*, – *Figure 56: LQFP32 marking example (package top view)*, – *Figure 59: VFQFPN32 marking example (package top view)*, – the footnote about the device marking to *Figure 60: STM8AF526x/8x/Ax and STM8AF6269/8x/Ax ordering information scheme1*. Removed STM8AF51xx and STM8AF61xx obsolete root part numbers, and consequently “H” products: – *Table 1: Device summary*, – *Section 1: Introduction*, – *Section 2: Description*, – *Section 3: Product line-up*, – *Table 12: Memory model 128K*, – *Section 10.3: Operating conditions*, – *Figure 60: STM8AF526x/8x/Ax and STM8AF6269/8x/Ax ordering information scheme1*. Moved *Section 11.6: Thermal characteristics* to *Section 11: Package information*. Updated: – the product naming in the document headers and captions, – the standard reference for EMI characteristics in *Table 46: EMI data*.
13-Jun-2016	13	Updated *Table 53: VFQFPN32 - 32-pin, 5 x 5 mm, 0.5 mm pitch very thin profile fine pitch quad flat package mechanical data*